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- 3-State Buffer-Type Outputs Drive Bus Lines Directly
- Bus-Structured Pinout
- Inverting-Logic Outputs
- Package Options Include Plastic Small-Outline (DW) Packages, Ceramic Chip Carriers (FK), Standard Plastic (N) and Ceramic (J) 300-mil DIPs, and Ceramic Flat (W) Packages

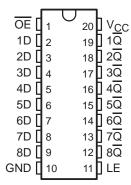
### description

These octal D-type transparent latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. They are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

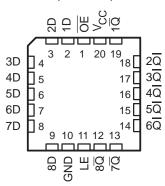
While the latch-enable (LE) input is high, outputs  $(\overline{Q})$  respond to the data (D) inputs. When LE is low, the outputs are latched to retain the data that was set up.

A buffered output-enable ( $\overline{OE}$ ) input can be used to place the eight outputs in either a normal logic state (high or low) or a high-impedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and the increased drive provide the capability to drive bus lines without interface or pullup components.

SN54ALS580B . . . J OR W PACKAGE SN74ALS580B, SN74AS580 . . . DW OR N PACKAGE (TOP VIEW)



SN54ALS580B . . . FK PACKAGE (TOP VIEW)



OE does not affect internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ALS580B is characterized for operation over the full military temperature range of -55°C to 125°C. The SN74ALS580B and SN74AS580 are characterized for operation from 0°C to 70°C.

## FUNCTION TABLE (each latch)

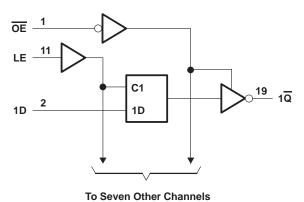
	INPUTS O				
OE	LE	D	Q		
L	Н	Н	L		
L	Н	L	н		
L	L	Χ	$\overline{Q}_0$		
Н	Х	Χ	Z		

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### logic symbol†

#### OE ΕN 11 C1 2 19 1D $\triangleright$ 1Q 1D $\nabla$ 3 18 2Q 2D 17 4 3D 3Q 5 16 4D 4Q 6 15 5Q 5D 7 14 6Q 6D 8 13 7Q 7D 9 12 8D 8Q

### logic diagram (positive logic)



### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage, V <sub>CC</sub>	
Input voltage, V <sub>I</sub>	7 V
Voltage applied to a disabled 3-state output	5.5 V
Operating free-air temperature range, T <sub>A</sub> : SN54ALS580B	−55°C to 125°C
SN74ALS580B	0°C to 70°C
Storage temperature range	-65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### recommended operating conditions

		SN54ALS580B		0B	SN74ALS580B			UNIT
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
VCC	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V <sub>IL</sub>	Low-level input voltage			0.7			0.8	V
IOH	High-level output current			-1			-2.6	mA
lOL	Low-level output current			12			24	mA
t <sub>W</sub>	Pulse duration, LE high	15			15			ns
t <sub>su</sub>	Setup time, data before LE↓	20			10			ns
t <sub>h</sub>	Hold time, data after LE↓	12			10			ns
T <sub>A</sub>	Operating free-air temperature	-55		125	0		70	°C

<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST C	ONDITIONS	SN5	SN54ALS580B		SN7	4ALS58	0B	UNIT
PARAMETER	1231 CC	TEST CONDITIONS		TYP <sup>†</sup>	MAX	MIN	TYP <sup>†</sup>	MAX	UNIT
VIK	V <sub>CC</sub> = 4.5 V,	$I_1 = -18 \text{ mA}$			-1.2			-1.2	V
	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -0.4 \text{ mA}$	V <sub>CC</sub> -2	2		V <sub>CC</sub> -2	!		
Voн	V <sub>CC</sub> = 4.5 V	I <sub>OH</sub> = -1 mA	2.4	3.3					V
	vCC = 4.5 v	$I_{OH} = -2.6 \text{ mA}$				2.4	3.2		
Va	V== -4.5.V	I <sub>OL</sub> = 12 mA		0.25	0.4		0.25	0.4	V
VOL	V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 24 mA					0.35	0.5	V
lozh	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.7 V			20			20	μΑ
lozL	$V_{CC} = 5.5 \text{ V},$	$V_0 = 0.4 \text{ V}$			-20			-20	μΑ
lį	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 7 V			0.1			0.1	mA
lін	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V			20			20	μΑ
I <sub>IL</sub>	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.4 V			-0.13			-0.1	mA
I <sub>O</sub> ‡	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-20		-112	-30		-112	mA
		Outputs high		10	17		10	17	
ICC	V <sub>CC</sub> = 5.5 V	Outputs low		16	26		16	26	mA
		Outputs disabled		17	29		17	29	

### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	ТО (ОИТРИТ)	$\begin{array}{c} \text{V}_{\text{CC}} = 4.5 \text{ V to } 5.5 \text{ V,} \\ \text{C}_{\text{L}} = 50 \text{ pF,} \\ \text{R1} = 500 \ \Omega, \\ \text{R2} = 500 \ \Omega, \\ \text{T}_{\text{A}} = \text{MIN to MAX\$} \\ \hline \text{SN54ALS580B}  \text{SN74ALS580B} \end{array}$			UNIT	
			MIN	MAX	MIN	MAX	
t <sub>PLH</sub>	D	_	3	26	3	18	20
t <sub>PHL</sub>		Q	3	15	3	14	ns
t <sub>PLH</sub>	LE	Q	8	29	6	22	ns
t <sub>PHL</sub>	LE	Q	4	22	6	21	115
<sup>t</sup> PZH	ŌĒ	Q	4	25	3	18	
t <sub>PZL</sub>		Q	4	21	4	18	ns
<sup>t</sup> PHZ	ŌĒ	Q	2	12	1	10	200
t <sub>PLZ</sub>	OE .		3	22	1	15	ns

<sup>§</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



<sup>†</sup> All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C. ‡ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, I<sub>OS</sub>.

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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V <sub>CC</sub>	7 V
Input voltage, V <sub>I</sub>	7 V
Voltage applied to a disabled 3-state output	
Operating free-air temperature range, T <sub>A</sub> : SN74AS580	0°C to 70°C
Storage temperature range	-65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

### recommended operating conditions

		SN74AS580			UNIT
		MIN	NOM	MAX	UNII
Vcc	Supply voltage	4.5	5	5.5	V
VIH	High-level input voltage	2			V
$V_{IL}$	Low-level input voltage			0.8	V
ЮН	High-level output current			-15	mA
loL	Low-level output current			48	mA
t <sub>W</sub> *	Pulse duration, LE high	2			ns
t <sub>su</sub> *	Setup time, data before LE↓	2			ns
th*	Hold time, data after LE↓	3			ns
TA	Operating free-air temperature	0		70	°C

<sup>\*</sup> On products compliant to MIL-STD-883, Class B, this parameter is based on characterization data but is not production tested.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

DADAMETED	TEGT COMPLE	FIONS	SN	174AS58	0	LINUT
PARAMETER	TEST CONDIT	IIONS	MIN	TYP‡	MAX	UNIT
VIK	$V_{CC} = 4.5 V,$	$I_{ } = -18 \text{ mA}$			-1.2	V
\/a	$V_{CC} = 4.5 \text{ V to } 5.5 \text{ V},$	$I_{OH} = -2 \text{ mA}$	V <sub>CC</sub> -2	!		V
Voн	V <sub>CC</sub> = 4.5 V,	I <sub>OH</sub> = -15 mA	2.4	3.3		V
V <sub>OL</sub>	$V_{CC} = 4.5 V,$	I <sub>OL</sub> = 48 mA		0.33	0.5	V
l <sub>OZH</sub>	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.7 V			50	μΑ
l <sub>OZL</sub>	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 0.4 V			-50	μΑ
lį	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 7 V			0.1	mA
lін	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 2.7 V			20	μΑ
IIL	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.4 V			-0.5	mA
I <sub>O</sub> §	V <sub>CC</sub> = 5.5 V,	V <sub>O</sub> = 2.25 V	-30		-112	mA
		Outputs high		62	100	
lcc	$V_{CC} = 5.5 V$	Outputs low		65	106	mA
		Outputs disabled		71	115	

 $<sup>\</sup>ddagger$  All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .



<sup>§</sup> The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

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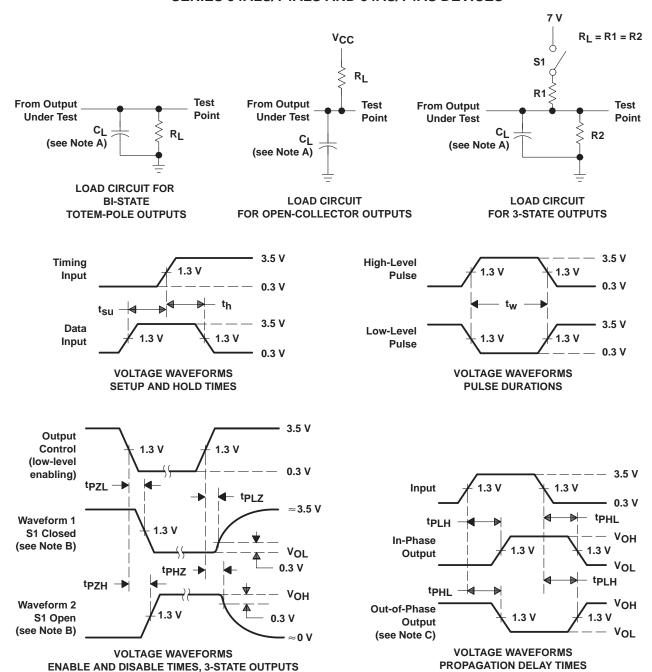
### switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC}$ = 4.5 V to 5.5 V, $C_L$ = 50 pF, R1 = 500 Ω, R2 = 500 Ω, $T_A$ = MIN to MAX <sup>†</sup> SN74AS580 MIN MAX		$C_L$ = 50 pF, R1 = 500 $\Omega$ , R2 = 500 $\Omega$ , $T_A$ = MIN to MAX <sup>†</sup> SN74AS580		UNIT
t <sub>PLH</sub>	D	=	3	7.5			
t <sub>PHL</sub>		₫	3	7	ns		
t <sub>PLH</sub>	LE	Ī	5	9			
t <sub>PHL</sub>	LE	LE Q	4	8	ns		
<sup>t</sup> PZH	<del></del>	ā	2	6.5			
t <sub>PZL</sub>	ŌĒ	Q	4	9.5	ns		
<sup>t</sup> PHZ	ŌĒ	Q	2	6.5	ne		
<sup>t</sup> PLZ	OE .	OE Q	2	7	ns		

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

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# PARAMETER MEASUREMENT INFORMATION SERIES 54ALS/74ALS AND 54AS/74AS DEVICES



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR  $\leq$  1 MHz,  $t_{\Gamma} = t_{f} = 2$  ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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